

ZXMN2F30FH 20V SOT23 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	$R_{DS(on)}(\Omega)$	I _D (A)
20	0.045 @ V _{GS} = 4.5V	4.9
	0.065 @ V _{GS} = 2.5V	4.1



Description

This new generation Trench MOSFET from Zetex features low onresistance achievable with low (2.5V) gate drive.

Features

- · Low on-resistance
- · 2.5V gate drive capability
- SOT23 package

Applications

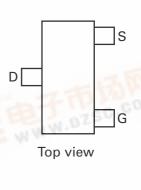
- Buck/Boost DC-DC Converters
- · Load switching and SMPS
- · Charging applications in portable equipment
- Motor Control
- LED Lighting

Ordering information

DEVICE	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2F30FHTA	7	8	3000

Device marking

KNC



Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	20	V
Gate source voltage	V _{GS}	±12	V
Continous Drain Current @ V _{GS} =4.5; T _A =25°C ^(b)	I _D	4.9	A
@ V _{GS} =4.5; T _A =70°C ^(b) @ V _{GS} =4.5; T _A =25°C ^(a)		4.0 4.1	A A
Pulsed drain current ^(c)	I _{DM}	22.6	Α
Continuous source current (body diode)(b)	I _S	1.6	Α
Pulsed source current (body diode)(c)	I _{SM}	22.6	Α
Power dissipation at T _A =25°C ^(a)	P _D	0.96	W
Linear derating factor		7.6	mW/°C
Power dissipation at T _A =25°C ^(b)	P _D	1.4	W
Linear derating factor		11.2	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	131	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	89	°C/W
Junction to Lead ^(d)	$R_{\Theta JL}$	68	°C/W

NOTES:

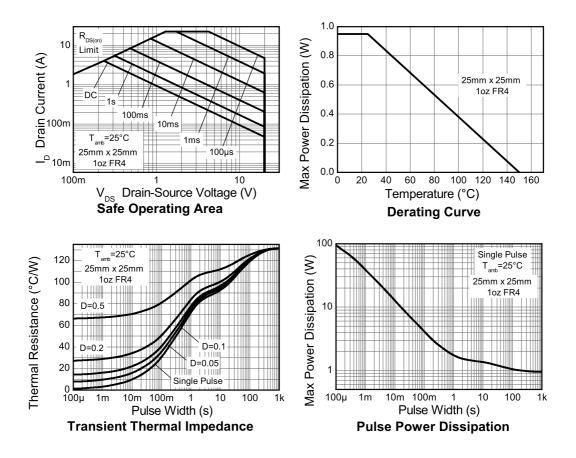
⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

⁽b) For a device surface mounted on FR4 PCB measured at t≤ 5 sec.

⁽c) Repetitive rating - $25mm \times 25mm \text{ FR4 PCB}$, D=0.02, pulse width $300\mu\text{s}$ - pulse width limited by maximum junction temperature.

⁽d) Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal characteristics



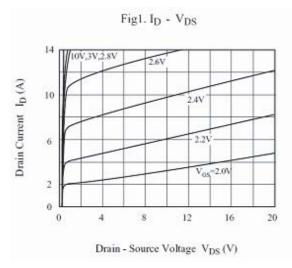
Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

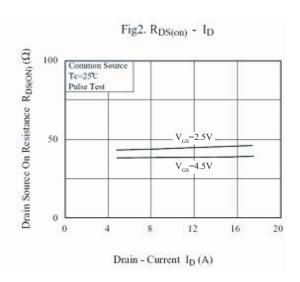
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	20			V	I_{D} = 250 μ A, V_{GS} =0V
Zero Gate Voltage Drain Current	I _{DSS}			1	μΑ	V _{DS} = 20V, V _{GS} =0V
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±12V, V _{DS} =0V
Gate-Source Threshold Voltage	V _{GS(th)}	0.6	0.9	1.5	V	$I_D=250\mu A, V_{DS}=V_{GS}$
Static Drain-Source	R _{DS(on)}			0.045	Ω	V _{GS} = 4.5V, I _D = 2.5A
On-State Resistance (*)				0.065	Ω	V_{GS} = 2.5V, I_{D} = 2.0A
Forward	9 _{fs}		8.6		S	V_{DS} = 10V, I_{D} = 3A
Transconductance ^{(*)(†)}						
Dynamic ^(†)						
Input Capacitance	C _{iss}		452		рF	10)/)/
Output Capacitance	C _{oss}		102		pF	V _{DS} = 10V, V _{GS} =0V f=1MHz
Reverse Transfer Capacitance	C _{rss}		58		pF	- 1111112
Switching (‡)(†)						
Turn-On-Delay Time	t _{d(on)}		2.9		ns	
Rise Time	t _r		5.6		ns	V _{DD} = 10V, V _{GS} = 4.5V I _D = 1A
Turn-Off Delay Time	t _{d(off)}		19.4		ns	$R_G \approx 6.0\Omega$
Fall Time	t _f		10.2		ns	
Total Gate Charge	Q_g		4.8		nC	V _{DS} = 10V, V _{GS} = 4.5V
Gate-Source Charge	Q_{gs}		1		nC	I _D = 3.5A
Gate Drain Charge	Q_{gd}		1.2		nC	1
Source-drain diode			I	1		•
Diode Forward Voltage ^(*)	V_{SD}		0.75	1.2	V	I _S = 1.25A, V _{GS} =0V

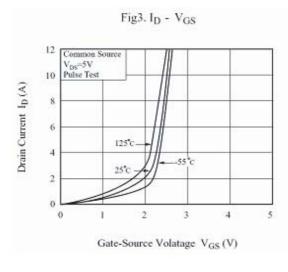
^(*) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

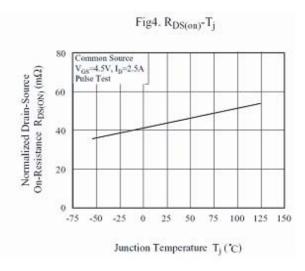
^(†) For design aid only, not subject to production testing.
(‡) Switching characteristics are independent of operating junction temperature.

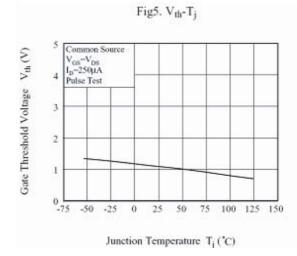
Typical characteristics

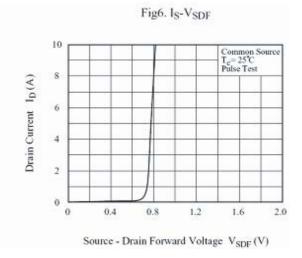




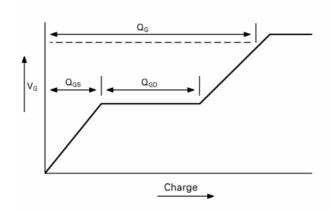


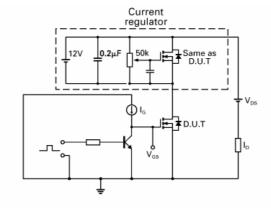






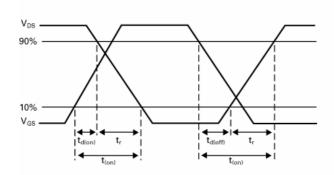
Test circuits

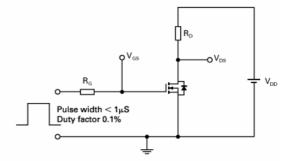




Basic gate charge waveform

Gate charge test circuit

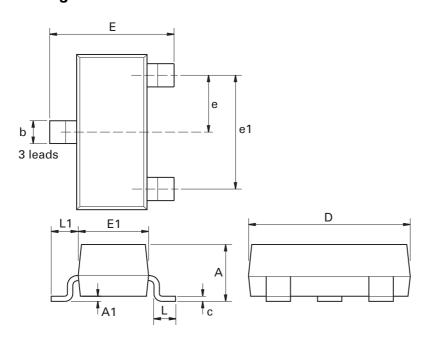




Switching time waveforms

Switching time test circuit

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	-	1.12	-	0.044	e1	1.90 NOM		0.075 NOM	
A1	0.01	0.10	0.0004	0.004	Е	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.20	0.003	0.008	L	0.25	0.60	0.0098	0.0236
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.037	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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